



Attention: Mail Stop AF  
Response Under 37 C.F.R. § 1.116  
Expedited Procedure Requested  
Examining Group 2823

PATENT  
Customer No. 22,852  
Attorney Docket No. 04329.2335

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Tokuhiwa OHIWA, et al.

Serial No.: 09/604,724

Filed: June 28, 2000

For: HIGH PRECISION PATTERN  
FORMING METHOD OF  
MANUFACTURING A  
SEMICONDUCTOR DEVICE (AS  
AMENDED)

Group Art Unit: 2823

Examiner: Maldonado, Julio J.

*Amat CMO*

9/12/03  
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2003  
TECHNOLOGY CENTER 2800

MAIL STOP AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**AMENDMENT AFTER FINAL**

In reply to the Final Office Action of June 24, 2003, with a period for response extending through September 24, 2003, Applicants propose amending the application as follows, and respectfully request the Examiner's reconsideration in view of remarks that follow:

**Amendments to the Claims** are reflected in the listing of claims beginning on page 2 of this paper.

**Remarks** begin on page 9 of this paper.

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